

#### **General Description**

The WST3078 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the small power switching and load switch applications.

The WST3078 meet the RoHS and Green Product requirement with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

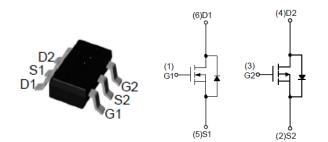
#### **Product Summery**

BVDSS	RDSON	ID
30V	32mΩ	3.5A
-30V	78mΩ	-3A

# **Applications**

- High Frequency Point-of-Load Synchronous s Small power switching for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

#### **SOT-23-6L Pin Configuration**



# **Absolute Maximum Ratings**

		Rating		
Symbol	Parameter	N-Channel	P-Channel	Units
$V_{DS}$	Drain-Source Voltage	30	-30	V
$V_{GS}$	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>c</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 4.5V <sup>1</sup>	3.5	-3	Α
I <sub>D</sub> @T <sub>c</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ 4.5V <sup>1</sup>	3.0	-2.4	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	19	-12	Α
P <sub>D</sub> @T <sub>A</sub> =25℃	Total Power Dissipation <sup>3</sup>	1.4	1.4	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	$^{\circ}$
$T_J$	Operating Junction Temperature Range	-55 to 150	-55 to 150	$^{\circ}$

#### **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>		125	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case <sup>1</sup>		90	°C/W



# N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.025		V/°C
_	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =2.7A		32	50	mΩ
R <sub>DS(ON)</sub>		V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A		56	68	11152
$V_{GS(th)}$	Gate Threshold Voltage	ate Threshold Voltage		1.6	2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250uA$		-2.54		mV/℃
	Drain Course Leakens Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =85℃			30	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±10	uA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =2A		11		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.3		Ω
Qg	Total Gate Charge (4.5V)			3		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =10V , I <sub>D</sub> =2A		1.1		nC
Q <sub>gd</sub>	Gate-Drain Charge			1.5		
T <sub>d(on)</sub>	Turn-On Delay Time			5.3	8	
Tr	Rise Time	V <sub>DD</sub> =10V , V <sub>GEN</sub> =4.5V ,		11	16	
T <sub>d(off)</sub>	Turn-Off Delay Time	$R_G=6\Omega I_D=2A R_L=10\Omega$		12	17	ns
T <sub>f</sub>	Fall Time			2.6	4	
C <sub>iss</sub>	Input Capacitance			215		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		37		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			28		

# **Drain-Source Body Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Continuous Source-Drain Diode Current <sup>1,4</sup>	V -V -0V Force Current			1.0	Α
I <sub>SM</sub>	Pulsed Diode Forward Current <sup>2,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			5	Α
V <sub>SD</sub>	Body Diode Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃		0.75	1.1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=5A , dI/dt=100A/μs , T <sub>J</sub> =25℃		9.2		nS
Q <sub>rr</sub>	Reverse Recovery Charge	IF=5A , αl/αl=100A/μs , 1J=25 C		4.3		nC

- 1.The data tested by Surface Mounted on 1in2 pad area. .

- 4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =-1mA		-0.013		V/°C
		V <sub>GS</sub> =-10V , I <sub>D</sub> =-2A		78	100	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1.5A		120	170	11122
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> . In =-250uA	-1.3	-1.6	-2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS , ID2300A		2.3		mV/℃
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =-24V , $V_{GS}$ =0V , $T_J$ =25 $^{\circ}$ C			-1	uA
DSS	Drain-Godice Leakage Guirent	$V_{DS}$ =-24V , $V_{GS}$ =0V , $T_J$ =85 $^{\circ}\mathrm{C}$			-30	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20V$ , $V_{DS}$ = $0V$			±10	uA
gfs	Forward Transconductance	$V_{DS}$ =-5V , $I_D$ =-2A		3.8		8
Qg	Total Gate Charge (-4.5V)			3.3		
$Q_gs$	Gate-Source Charge	V <sub>DS</sub> =-15V , V <sub>GS</sub> =-10V , I <sub>D</sub> =-2A		1.1		nC
$Q_gd$	Gate-Drain Charge			1.1		
T <sub>d(on)</sub>	Turn-On Delay Time			5.3	8	
T <sub>r</sub>	Rise Time	V <sub>DD</sub> =-15V , V <sub>GEN</sub> =-10V ,		9.3		no
T <sub>d(off)</sub>	Turn-Off Delay Time	$R_G$ =6Ω $I_D$ =-1A , $R_L$ =15Ω.		15.4		ns
T <sub>f</sub>	Fall Time			3.6		
C <sub>iss</sub>	Input Capacitance			229		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		42		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			33		

# **Drain-Source Body Diode Characteristics**

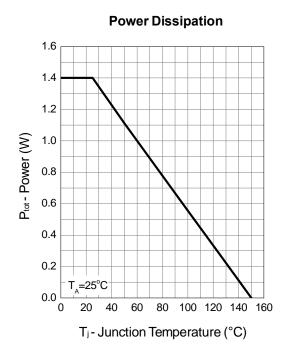
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Continuous Source-Drain Diode Current <sup>1,4</sup>	V =V =0V Force Current			-3.2	Α
I <sub>SM</sub>	Pulsed Diode Forward Current <sup>2,4</sup>	$V_G=V_D=0V$ , Force Current			-15	Α
V <sub>SD</sub>	Body Diode Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃		0.75	-1.1	V
t <sub>rr</sub>	Reverse Recovery Time			19		nS
Q <sub>rr</sub>	Reverse Recovery Charge	IF=-2A,dI/dt=100A/µs , T <sub>J</sub> =25℃		14		nC

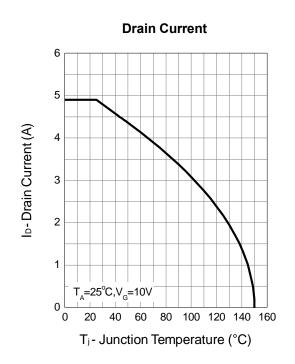
#### Note

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3.The power dissipation is limited by 150 ℃ junction temperature
- 4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

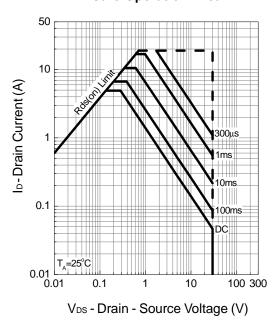


# **N-Channel Typical Characteristics**

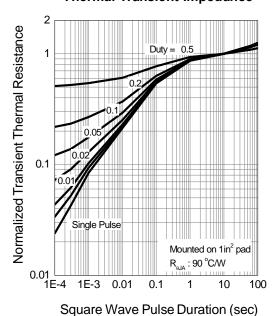




# Safe Operation Area

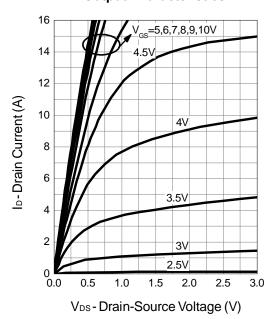


#### **Thermal Transient Impedance**

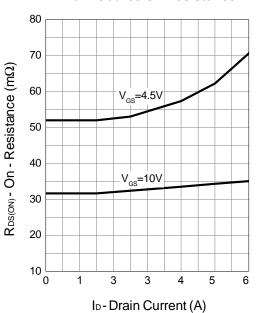




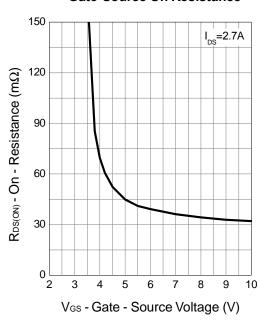




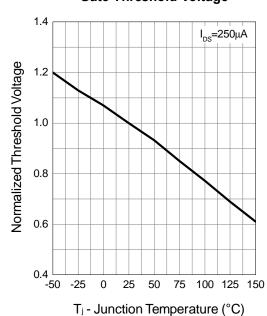
#### **Drain-Source On Resistance**



#### **Gate-Source On Resistance**

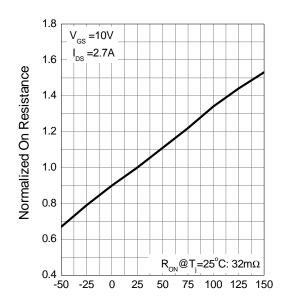


# **Gate Threshold Voltage**



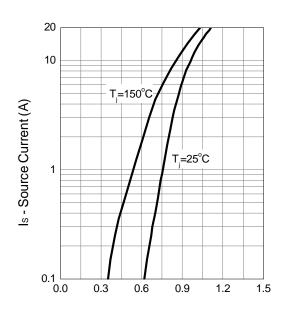


#### **Drain-Source On Resistance**



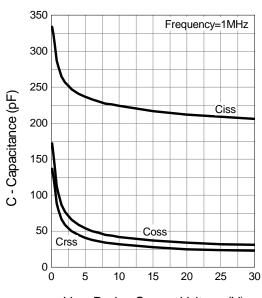
T<sub>j</sub>- Junction Temperature (°C)

# **Source-Drain Diode Forward**



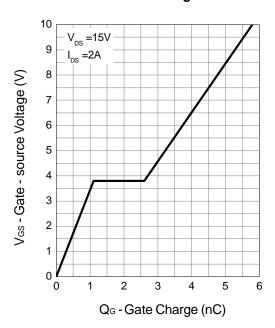
Vsp - Source - Drain Voltage (V)

#### Capacitance



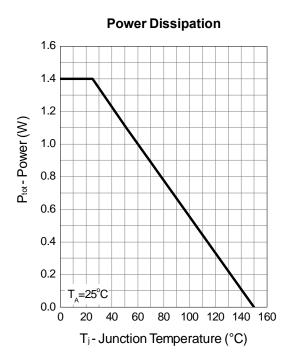
V<sub>DS</sub> - Drain - Source Voltage (V)

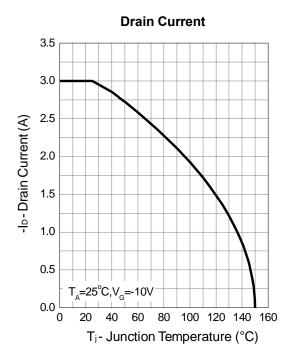
# **Gate Charge**



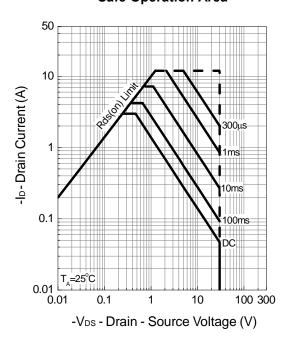


# **P-Channel Typical Characteristics**

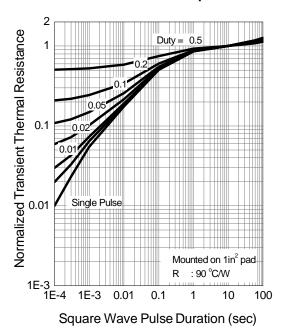




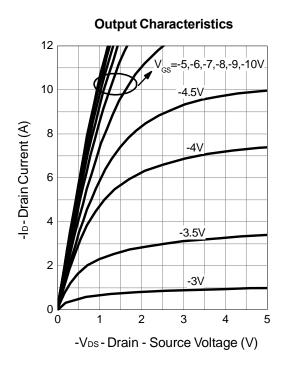
# Safe Operation Area

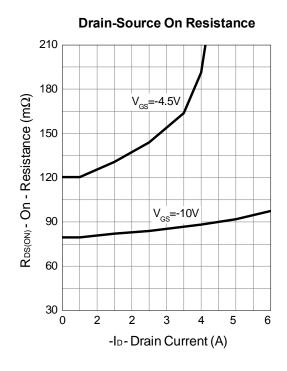


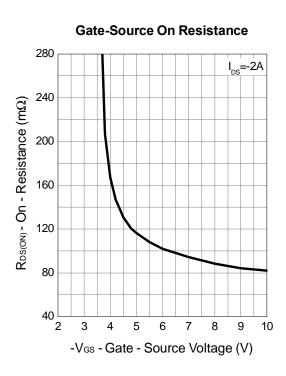
#### **Thermal Transient Impedance**

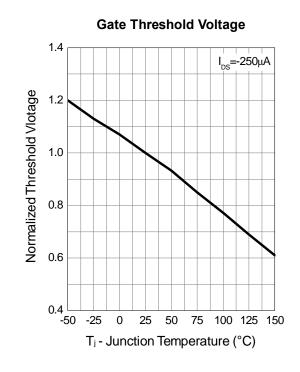








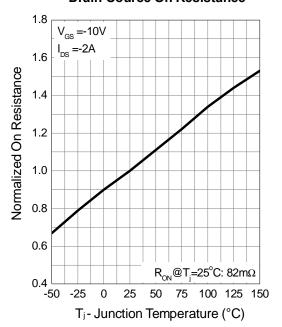




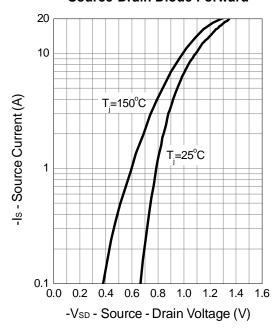




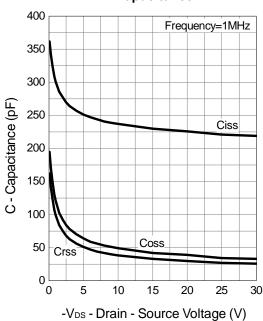
#### **Drain-Source On Resistance**



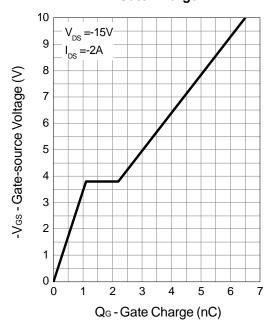
#### **Source-Drain Diode Forward**



# Capacitance



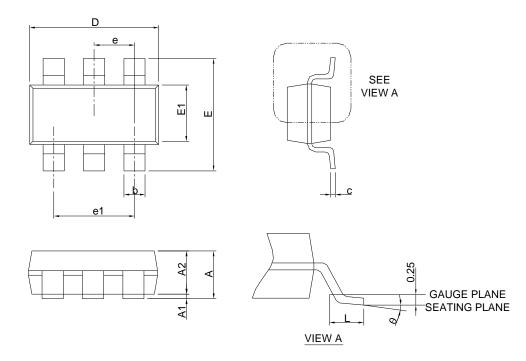
# Gate Charge





# Package Information

#### SOT-23-6

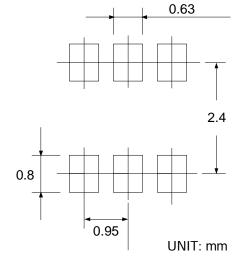


Ş		SOT-23-6			
SYMBO	MILLIM	ETERS	INC	HES	
P	MIN.	MAX.	MIN.	MAX.	
Α	-	1.25	-	0.049	
A1	0.00	0.05	0.000	0.002	
A2	0.90	1.20	0.035	0.047	
b	0.30	0.50	0.012	0.020	
С	0.08	0.22	0.003	0.009	
D	2.70	3.10	0.106	0.122	
Е	2.60	3.00	0.102	0.118	
E1	1.40	1.80	0.055	0.071	
е	0.95	BSC	0.037 BSC		
e1	1.90	BSC	0.07	5 BSC	
L	0.30	0.60	0.012	0.024	
θ	0°	8°	0°	8°	

Note: 1. Follow JEDEC TO-178 AB.

Dimension D and E1 do not include mold flash, protrusions or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 10 mil per side.

# **RECOMMENDED LAND PATTERN**





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